

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
MI22-1672SERIAL NO.
09/943.199LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Kristy A. Campbell, et al.FILING DATE
August 29, 2001GROUP
2818

U.S. PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
DV	AA	09/797,635		Moore			03/01/2001
	AB	09/732,968		Gilton			12/08/2000
	AC	09/943,190		Campbell et al.			08/29/2001
	AD	09/943,187		Campbell et al.			08/29/2001
	AE	09/779,983		Moore			02/08/2001
	AF	5,238,862	08/24/93	Bialock et al.			
	AG	5,360,981	11/01/94	Owen et al.			
	AH	5,761,115	06/02/98	Kozicki et al.			
	AI	5,896,312	04/20/99	Kozicki et al.			
	AJ	5,914,893	06/22/99	Kozicki et al.			
DV	AK	6,084,796	07/04/00	Kozicki et al.			

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AL							
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

DV	AR		Hirose, et al., "High Speed Memory Behavior and Reliability of an Amorphous As ₂ S ₃ Film Doped with Ag", July 17, 1980, pps K187-K190
DV	AS		Hirose, et al., "Polarity-dependent memory switching and behavior of Ag dendrite in Ag-photodoped amorphous As ₂ S ₃ films", Journal of Applied Physics, Vol. 47, No. 6, June, 1976, pps 2767-2772.
DV	AT		Kawaguchi, et al., "Optical, electrical, and structural properties of amorphous Ag-Ge-S and Ag-Ge-Se films and comparison of photoinduced and thermally induced phenomena of both systems", Journal of Applied Physics, 79, June 1996, pps 9096-9104

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DV	AR		Kluge, et al. "Silver photodiffusion in amorphous Ge ₂ Se ₁₀ ", Journal of Non-Crystalline Solids 124 (1990) pps. 186-193
DV	AS		Kolobov, A.V. "Photodoping of amorphous chalcogenides by metals", Advances in Physics, 1991, Vol. 40, No. 5, pps 625-684
DV	AT		Mitkova, et al. "Dual Chemical Role of Ag as an Additive in Chalcogenide Glasses", Physical Review Letters, Vol. 83, No. 19, pps 3848-3851

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DV	AR		Mitkova, "Insulating and Semiconducting Glasses", Editor: P. Boolchand, World Scientific, New Jersey, 2000, pps 813-843.
DV	AS		Axon Technologies Corporation, TECHNOLOGY DESCRIPTION: Programmable Metallization Cell (PMC).
			(pre-July 7, 2000) pp 1-6
DV	AT		Shimakawa et al., Photoinduced effects and metastability in amorphous semiconductors and insulators.
			44 ADVANCES IN PHYSICS No. 6, 475-588 (Taylor & Francis Ltd 1995)

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<div style="display: flex; align-items: center; justify-content: center;"> <div style="border: 1px solid black; border-radius: 50%; padding: 10px; text-align: center; margin-right: 10px;"> 1 PART JUN 26 2002 U.S. PATENT & TRADEMARK OFFICE </div> <div> LIST OF ART CITED BY APPLICANT (Use several sheets if necessary) </div> </div>				APPLICANT: Kristy A. Campbell et al.	
				FILING DATE 08/29/01	GROUP 2818

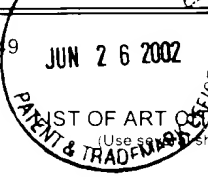
U.S. PATENT DOCUMENTS							
*Examiner Initial	Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
DV	AA	09/921,518	Moore (As filed and amended)			08/01/2001	
	AB	09/999,883	Moore et al. (as filed)			03/01/2001	
	AC	10/061,825	Gilton et al. (as filed)			01/31/2002	
	AD	4,405,710	09/20/83	Balasubramanyam et al.	430	311	
	AE	4,419,421	12/06/83	Wilchelhaus et al.	429	191	
	AF	4,499,557	02/12/85	Holmberg et al.	365	163	
	AG	5,315,131	05/24/94	Kishimoto et al.	257	57	
	AH	5,350,484	09/27/94	Gardner et al.	156	628	
	AI	5,512,328	04/30/96	Yoshimura et al.	427	498	
DV	AJ	5,512,773	04/30/96	Wolf et al.	257	471	

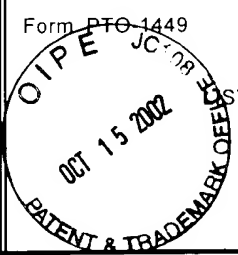
FOREIGN PATENT DOCUMENTS								
*Examiner Initial	Number	Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
DV	AK	56126916 A	05.10.81	Abstract: Japan (Akira et al.)			X	
	AL	00/48196 A1	17.08.00	WIPO (Kozicki et al.)				
	AM	09/21542 A1	14.03.02	WIPO (Kozicki et al.)				
	AN							
DV	AO							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
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U.S. PATENT DOCUMENTS									
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate			
DV	AA	5,846,889	12/08/98	Harbison et al.	501	40			
	AB	6,117,720	09/12/00	Harshfield	438	238			
	AC	6,143,604	11/07/00	Chiang et al.	438	253			
	AD	6,177,338 B1	01/23/01	Liaw et al.	438	629			
DV	AE	6,350,679 B1	02/26/02	McDaniel et al.	438	634			
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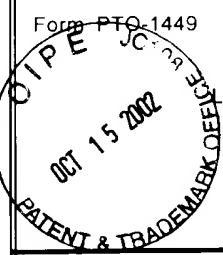
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
DV	AA	3,622,319	11/23/71	Sharp	96	27	
	AB	3,743,847	07/03/73	Boland	250	510	
	AC	4,269,935	05/26/81	Masters et al.	430	323	
	AD	4,312,938	01/26/82	Drexler et al.	430	496	
	AE	4,320,191	03/16/82	Yoshikawa et al.	430	296	
	AF	4,795,657	01/03/89	Formigoni et al.	427	96	
	AG	4,847,674	07/11/89	Silwa et al.	357	67	
	AH	5,177,567	01/05/93	Klersy et al.	257	4	
	AI	5,219,788	06/15/93	Abernathey et al.	437	187	
	AJ	5,726,083	03/10/98	Takaishi	438	210	
DV	AK	5,751,012	05/12/98	Wolstenholme et al.	257	5	

FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
DV	AN		Das et al., <i>Theory of the characteristic curves of the silver chalcogenide glass inorganic photoresists</i> , 54 APPL. PHYS. LETT., No. 18, pp. 1745-1747 (May 1989).
	AO		Helbert et al., <i>Intralevel hybrid resist process with submicron capability</i> , SPIE Vol. 333
			SUBMICRON LITHOGRAPHY pp. 24-29 (1982)
DV	AP		Hilt, DISSERTATION: <i>Materials Characterization of Silver Chalcogenide Programmable Metallization</i>
			Cells, Arizona State University, pp. title page-114 (UMI Company, May 1999).

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*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
DV	AA	5,789,277	08/04/98	Zahorik et al.	438	95	
	AB	5,841,150	11/24/98	Gonzalez et al.	257	3	
	AC	5,920,788	07/06/99	Reinberg	438	466	
	AD	5,998,066	12/07/99	Block et al.	430	5	
	AE	6,077,729	06/20/00	Harshfield	438	128	
	AF	6,236,059 B1	05/22/01	Wolstenholme et al.	257	3	
	AG	6,297,170 B1	10/02/01	Gabriel et al.	438	738	
	AH	6,300,684 B1	10/09/01	Gonzalez et al.	257	774	
	AI	6,316,784 B1	11/13/01	Zahorik et al.	257	3	
	AJ	6,329,606 B1	12/11/01	Freyman et al.	174	260	
DV	AK	6,348,365	02/19/02	Moore et al.	438	130	

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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
DV	AN		Holmquist et al., <i>Reaction and Diffusion in Silver-Arsenic Chalcogenide Glass Systems</i> ,
			62 J. AMER. CERAMIC SOC., Nos. 3-4, pp. 183-188 (Mar.-Apr. 1979).
	AO		Huggett et al., <i>Development of silver sensitized germanium selenide photoresist by reactive</i>
			<i>sputter etching in SF₆</i> , 42 APPL. PHYS. LETT., No. 7, pp. 592-594 (April 1983).
DV	AP		Kawaguchi et al., <i>Mechanism of photosurface deposition</i> , 164-166 J. NON-CRYST. SOLIDS,
			pp. 1231-1234 (1993).

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DV	AA	6,376,284 B1	04/23/02	Gonzalez et al.	438	129	
	AB	6,391,688 B1	05/21/02	Gonzalez et al.	438	128	
	AC	6,414,376 B1	07/02/02	Thakur et al.	257	640	
	AD	6,418,049 B1	07/09/02	Kozicki et al.	365	174	
DV	AE	6,423,628 B1	07/23/02	Li et al.	438	622	
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DV	AN	McHardy et al., <i>The dissolution of metals in amorphous chalcogenides and the effects of electron and ultraviolet radiation</i> , 20 J. PHYS. C: SOLID STATE PHYS., pp. 4055-4075 (1987).
	AO	Miyatani, <i>Electrical Properties of Ag₂Se</i> , 13 J. Phys. Soc. Japan, p. 317 (1958).
DV	AP	Mizusaki et al. <i>Kinetic Studies on the Selenization of Silver</i> , 47 BUL. CHEM. SOC. JAPAN., No. 11
		pp. 2851-2855 (November 1974).

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DV	AA	10/077,867		Campbell et al. (as filed)			02/20/2002
DV	AB	10/232,757		Li, et al. (as filed)			08/29/2002
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DV	AN		Owen et al., <i>Metal-Chalcogenide Photoresists for High Resolution Lithography and Sub-Micron Structures</i> , NANOSTRUCTURE PHYSICS AND FABRICATION, pp. 447-451 (Academic Press, 1989).
			Safran et al., <i>TEM study of Ag₂Se developed by the reaction of polycrystalline silver films and selenium</i> , 317 THIN SOLID FILMS, pp. 72-76 (1998).
DV	AP		Shimizu et al., <i>The Photo-Erasable Memory Switching Effect of Ag Photo-Doped Chalcogenide Glasses</i> , 46 BUL. CHEM. SOC. JAPAN, No. 12, pp. 3662-3665 (December 1973).

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DV	AN		Somogyi et al., <i>Temperature Dependence of the Carrier Mobility in Ag₂Se Layers Grown on NaCl and SiO_x Substrates</i> , 74 ACTA PHYSICA HUNGARICA, No. 3, pp. 243-255 (1994).
DV	AO		Tai et al., <i>Multilevel Ge-Se film based resist systems</i> , SPIE Vol. 333 SUBMICRON LITHOGRAPHY, pp. 32-39 (March 1982).
DV	AP		Tai et al., <i>Submicron optical lithography using an inorganic resist/polymer bilevel scheme</i> , 17 J. Vac. Sci. Technol., No. 5, pp. 1169-1176 (Sept./Oct. 1980).

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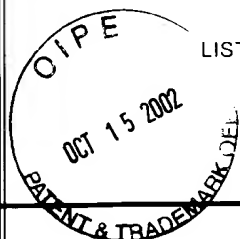
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DV	AN		West, DISSERTATION: <i>Electrically Erasable Non-Volatile Memory Via electrochemical Deposition of Multifractal Aggregates</i> , Arizona State University, pp. title page-168 (UMI Co., May 1998).
DV	AO		West et al., <i>Equivalent Circuit Modeling of the $\text{Ag} \text{As}_{0.24}\text{S}_{0.36}\text{Ag}_{0.40} \text{Ag}$ System Prepared by Photodissolution of Ag</i> , 145 J. Electrochem. Soc., No. 9, pp. 2971-2974 (September 1998).
DV	AP		Yoshikawa et al., <i>A new inorganic electron resist of high contrast</i> , 31 APPL. PHYS. LETT., No. 3, pp. 161-163 (August 1977).

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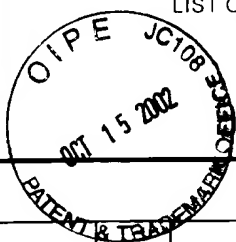
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DV	AN		Yoshikawa et al., <i>Dry development of Se-Ge Inorganic photoresist</i> , 36 APPL. PHYS. LETT., No. 1, pp. 107-109 (January 1980).
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PTO/SB/08A (10-01)

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Substitute for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)			Complete if Known		
			Application Number	09/943,199	
			Filing Date	August 29, 2001	
			First Named Inventor	Kristy A. Campbell	
			Art Unit	2818	
			Examiner Name	David Vu	
Sheet	1	of	1	Attorney Docket Number	M4065.0704/P704

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code ² (if known)			
DV		2002/0168820 A1	11-14-02	Kozicki et al.	
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Examiner Initials*	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
		Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)				

¹ Applicant's unique citation designation number (optional). ² See attached Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the application number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²

Examiner Signature	<i>David Vu</i>	Date Considered	01/08/03
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